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Zhu et al.

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(54) **INDUSTRIAL SIGNAL TESTING
EQUIPMENT FOR WIRELESS DEVICES**

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(52) **U.S. Cl.**
USPC **D10/78**

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G01N 21/85; G01N 33/1826; G01N
21/51; G01N 2021/8571; G01N
2201/062; B01D 29/60; B01D 35/143;
B01D 29/96; C02F 1/003; C02F 1/283;
C02F 2209/06; C02F 2209/10; C02F
2209/20; C02F 2307/06; Y02A 20/20;
G01V 3/15; G01R 11/04; G01R 11/24
See application file for complete search history.

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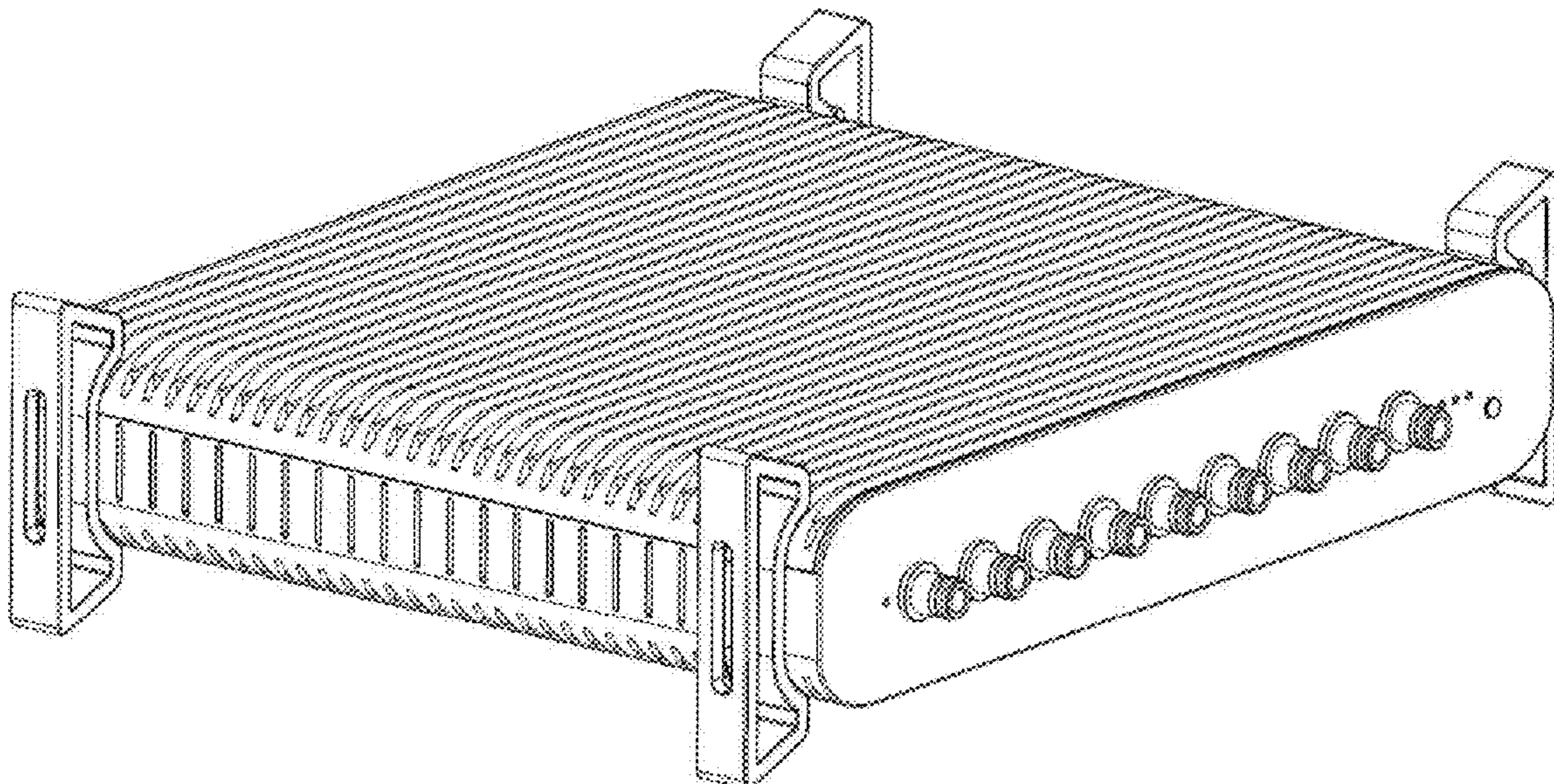
(57) **CLAIM**

The ornamental design for an industrial signal testing equip-
ment for wireless devices, as shown and described.

DESCRIPTION

FIG. 1 is a front perspective view of the industrial signal
testing equipment for wireless devices;
FIG. 2 is a rear perspective view thereof;
FIG. 3 is a front elevational view thereof;
FIG. 4 is a rear elevational view thereof;
FIG. 5 is a left side elevational view thereof;
FIG. 6 is a right side elevational view thereof;
FIG. 7 is a top plan view thereof; and,
FIG. 8 is a bottom plan view thereof.

1 Claim, 8 Drawing Sheets



(56)

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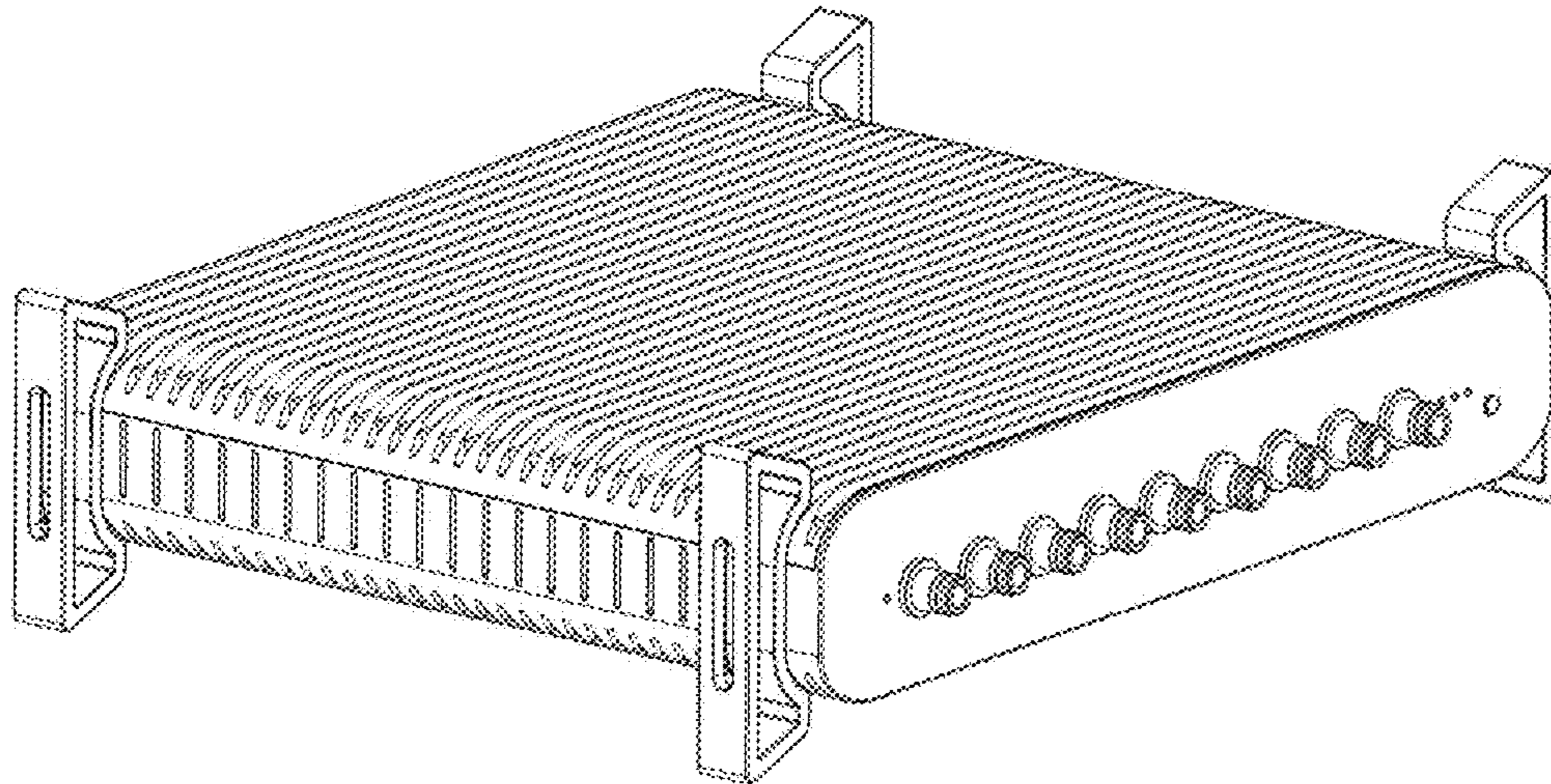


FIG. 1

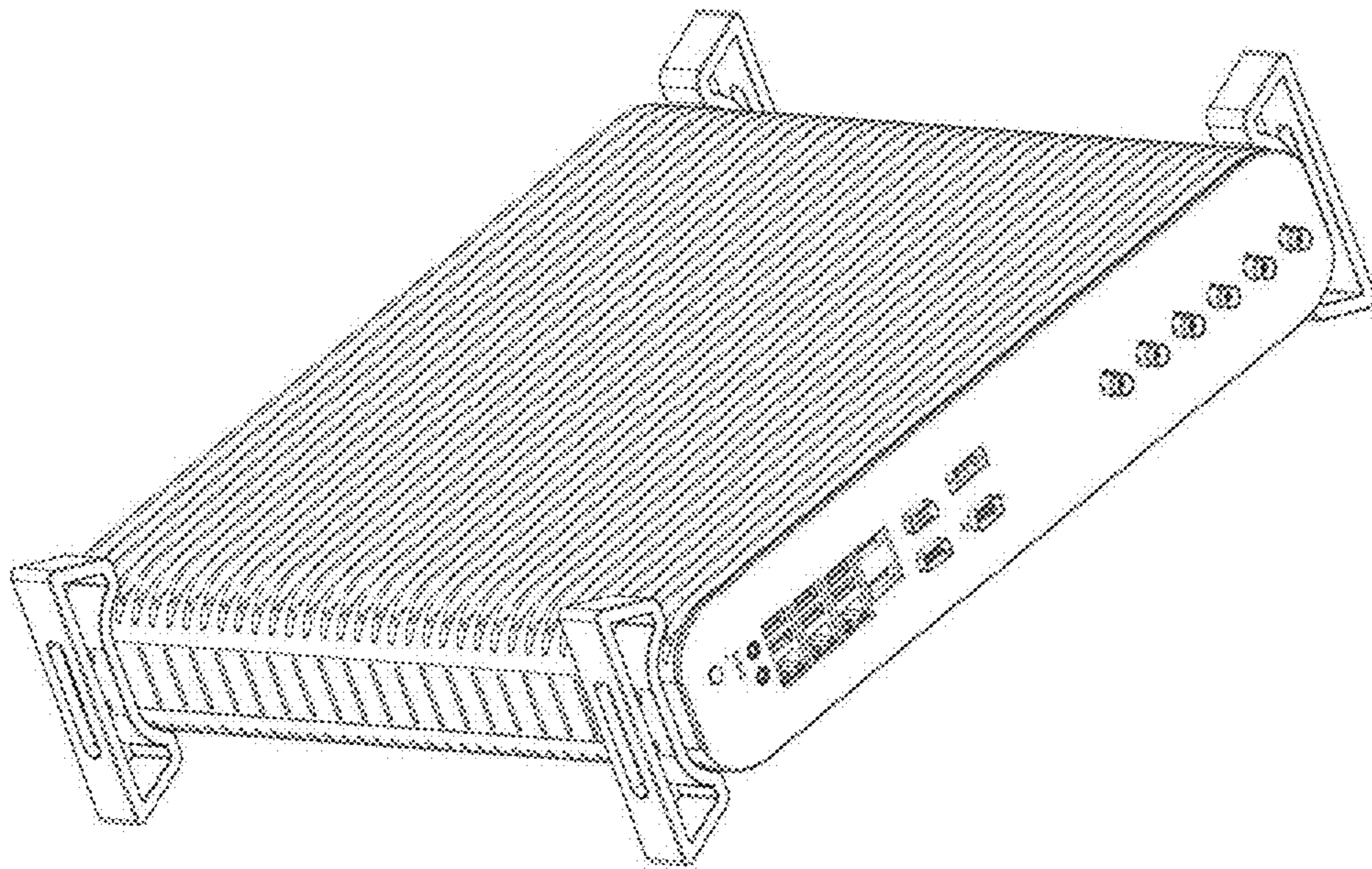


FIG. 2

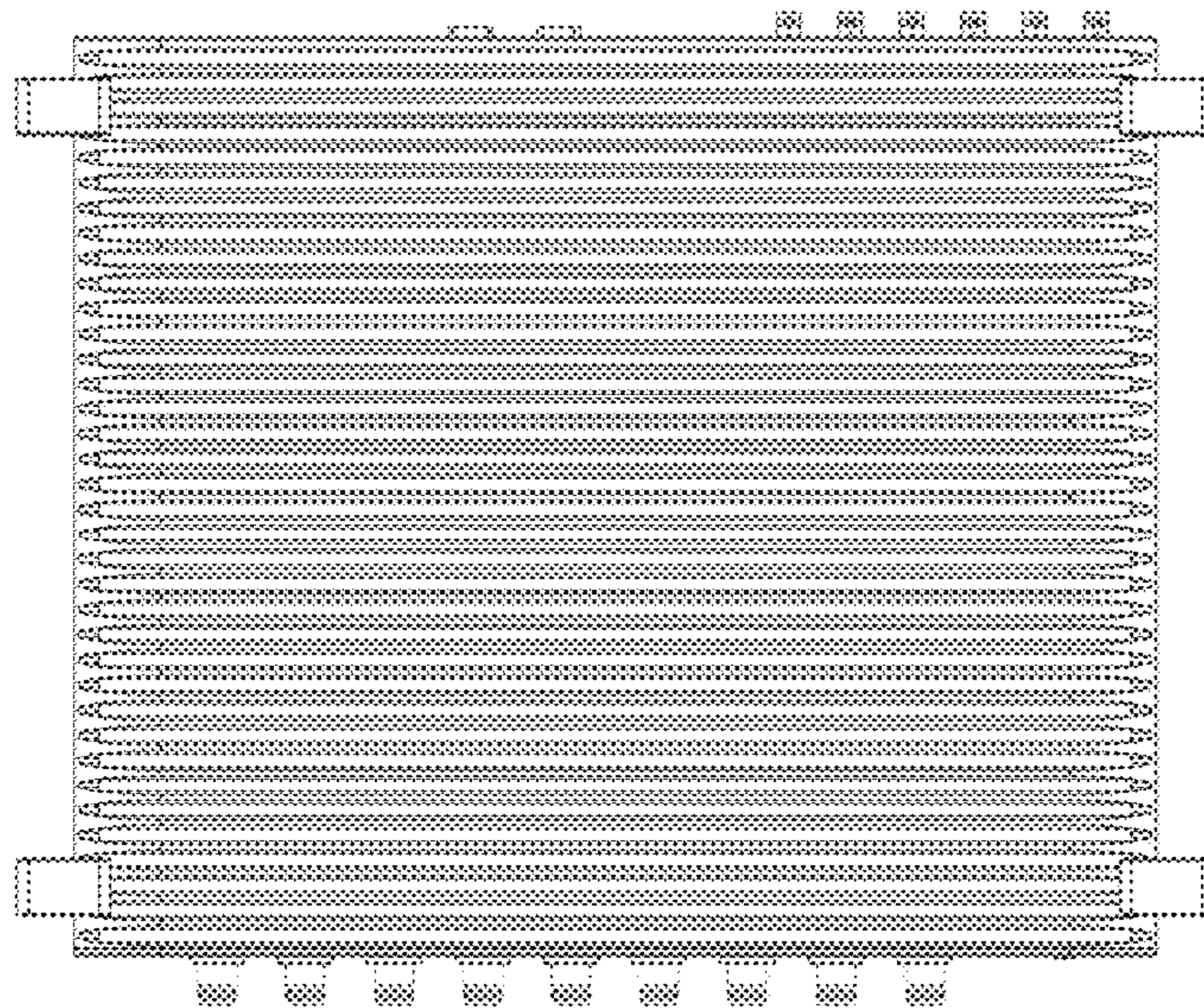


FIG. 3

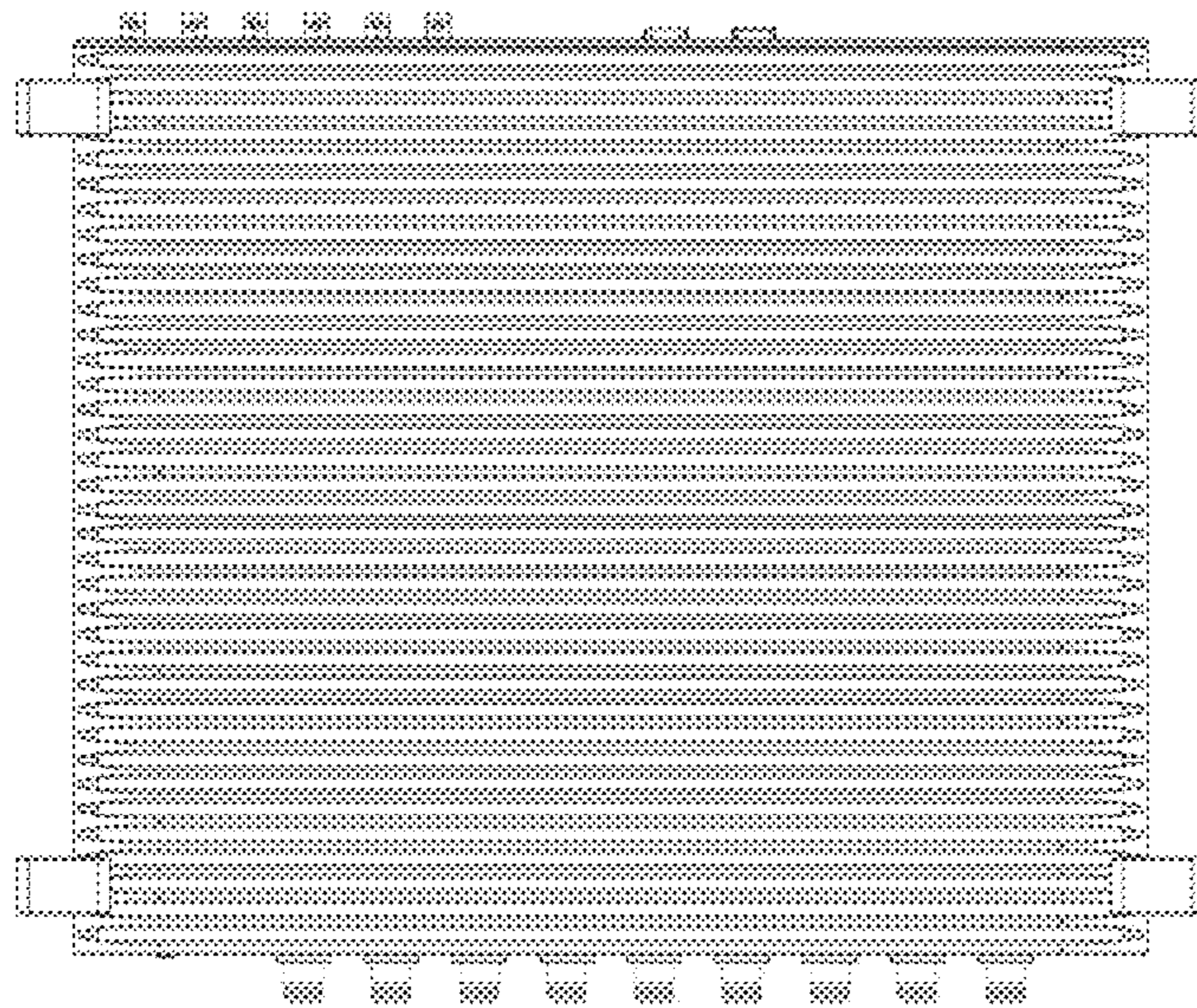


FIG. 4

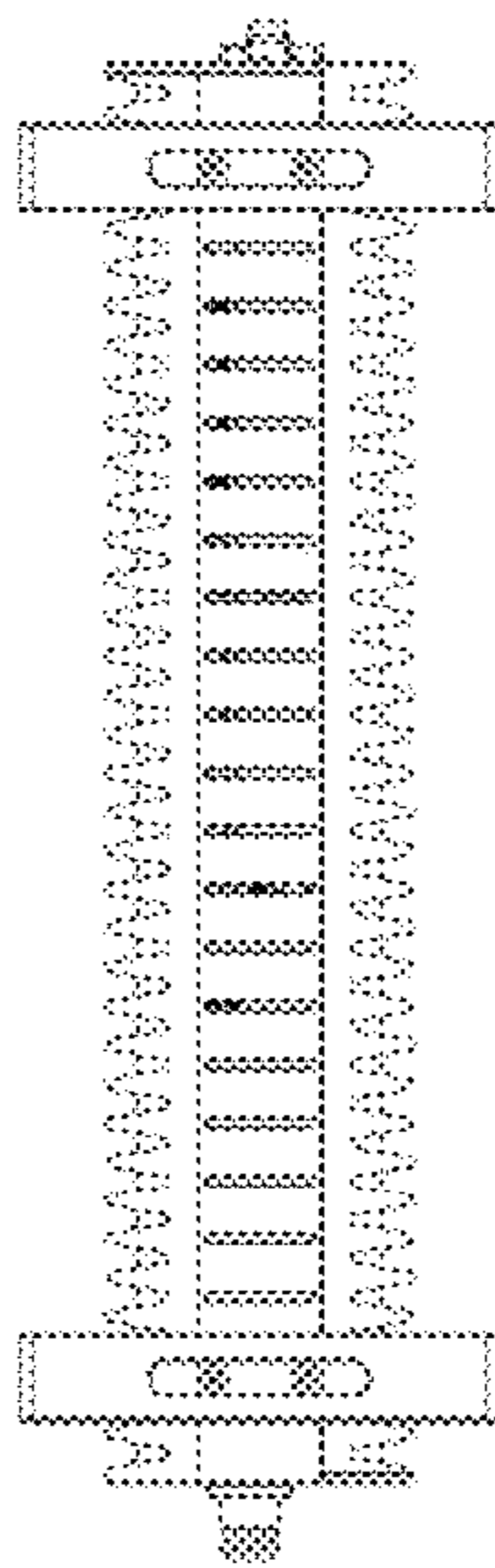


FIG. 5

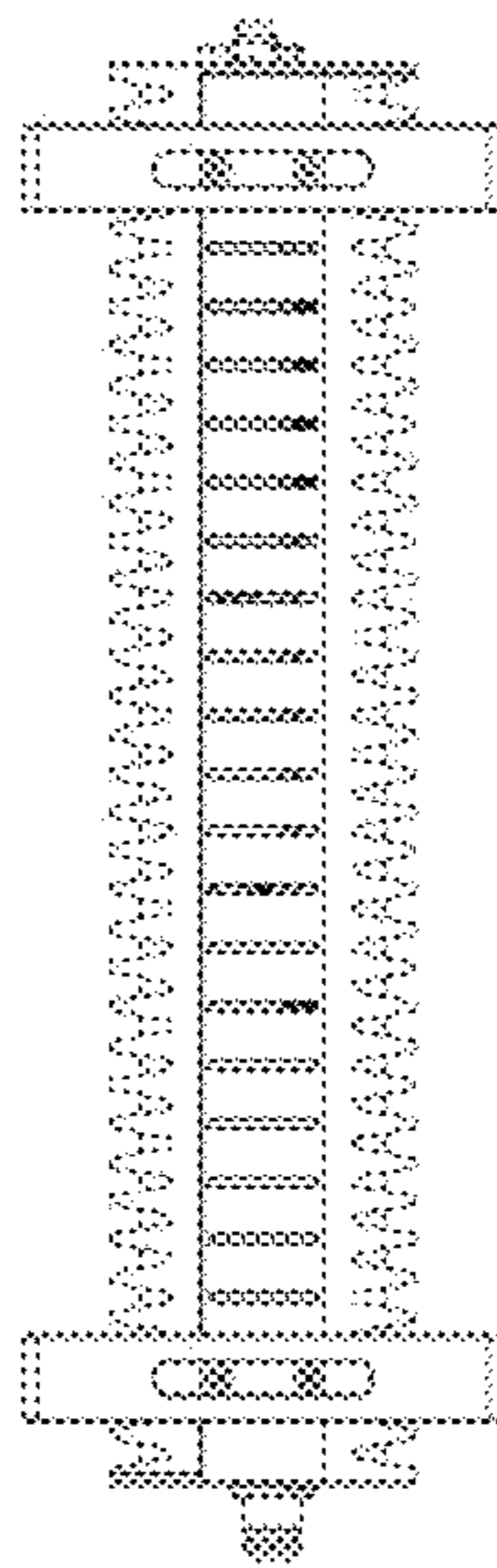


FIG. 6

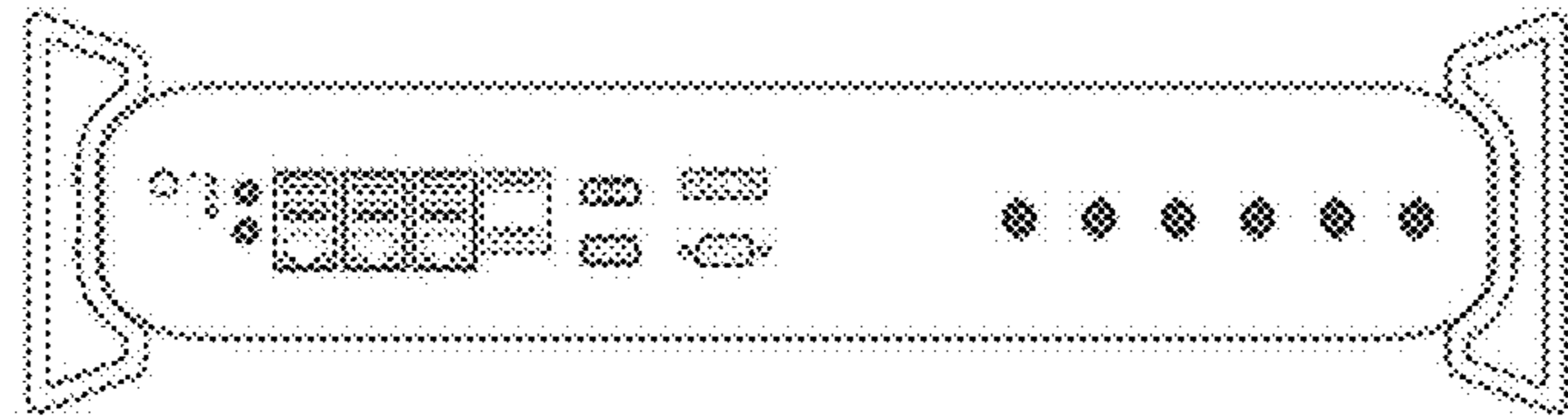


FIG. 7

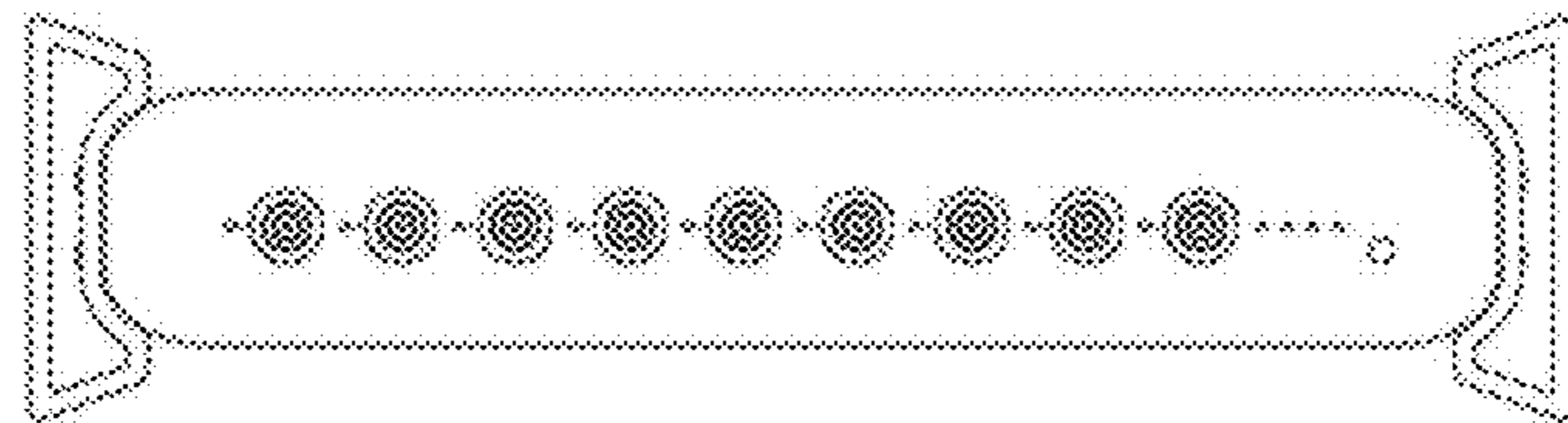


FIG. 8